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I claim:

A method for determining patent license fee data, comprising:
inputting on a computer patent license data;

processing the patent license data using an interaction involving the computer to determine patent license fee data; and

outputting on the computer the patent license fee data,

wherein the processing step includes determining algorithmically exposure rate data to be applied in determining the patent license fee data.

- 2. The method according to claim 1, wherein the processing step includes determining exposure rate data to be applied in determining the patent license fee data in function of a patent count.
- 3. The method according to claim 1, wherein the processing step includes determining exposure rate data to be applied in determining the patent license fee data in function of a patent strength metric.
- 4. The method according to claim 1, wherein the processing step includes determining exposure rate data to be applied in determining the patent license fee data in function of a patent count and a patent strength metric.
- 5. A networked computing system, comprising an end-user station having a user interface, for interacting with a user, and a network interface, for interacting with a network, wherein the end-user station interacts with the user and the network to determine patent license fee data including determining

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algorithmically exposure rate data to be applied in determining the patent license fee data.

- 6. The system according to claim 5, wherein the exposure rate data are determined in function of a patent count.
- 7. The system according to claim 5, wherein the exposure rate data are determined in function of a patent strength metric.
- 8. The system according to claim 5, wherein the exposure rate data are determined in function of a patent count and a patent strength metric.
- 9. A computer program having instructions for interacting with an enduser station, a user and a network to determine patent license fee data including determining algorithmically exposure rate data to be applied in determining the patent license fee data.
- 10. The program according to claim 9, wherein the exposure rate data are determined in function of a patent count.
- 11. The program according to claim 9, wherein the exposure rate data are determined in function of a patent strength metric.
- 12. The program according to claim 9, wherein the exposure rate data are determined in function of a patent count and a patent strength metric.
- 13. A method for determining patent license fee data, comprising: identifying a patent count; calculating exposure rate data in function of the patent count; calculating patent license fee data in function of the exposure rate data.

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14. The method according to claim 13, further comprising:

identifying a patent strength metric,

wherein the exposure rate data are calculated in further function of the patent strength metric.

15. A method for determining exposure rate data for application in determining patent license fee data, comprising:

identifying a plurality of exposure rate function parameters;

defining an exposure rate function using the plurality of exposure rate function parameters;

identifying a patent count; and

applying the patent count in the exposure rate function to determine exposure rate data.

16. The method according to claim 15, further comprising: identifying a patent strength parameter; and

adjusting the exposure rate function using the patent strength parameter prior to applying the patent count in the exposure rate function.

- 17. The method according to claim 15, wherein the exposure rate function parameters include a minimum patent threshold and a per patent exposure rate.
- 20 18. The method according to claim 15, wherein the plurality of exposure rate function parameters includes a per patent exposure rate and a maximum patent threshold.

- 19. The method according to claim 15, wherein the plurality of exposure rate function parameters includes a minimum patent threshold and a maximum patent threshold.
- 20. The method according to claim 15, wherein the plurality of exposure rate function parameters includes a maximum exposure rate.
 - 21. The method according to claim 15, wherein the exposure rate function is linear.